### SN54BCT241, SN74BCT241 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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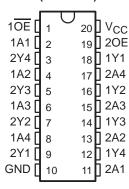
- State-of-the-Art BiCMOS Design Significantly Reduces I<sub>CCZ</sub>
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- Package Options Include Plastic Small-Outline (DW) and Shrink Small-Outline (DB) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic and Ceramic 300-mil DIPs (J, N)

#### description

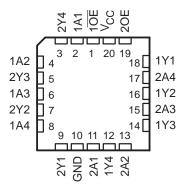
These octal buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. Taken together with the 'BCT240 and 'BCT244, these devices provide the choice of selected combinations of inverting and noninverting outputs, symmetrical  $\overline{\text{OE}}$  (active-low output-enable) inputs, and complementary OE and  $\overline{\text{OE}}$  inputs.

The SN54BCT241 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The SN74BCT241 is characterized for operation from 0°C to 70°C.

#### SN54BCT241 ... J OR W PACKAGE SN74BCT241 ... DB, DW OR N PACKAGE (TOP VIEW)



## SN54BCT241 . . . FK PACKAGE (TOP VIEW)



#### **FUNCTION TABLES**

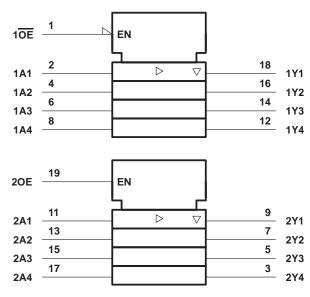
INP	JTS	OUTPUT				
1OE	1A	1Y				
L	Н	Н				
L	L	L				
Н	Х	Z				

INP	JTS	OUTPUT
20E	2A	2Y
Н	Н	Н
Н	L	L
L	Χ	Z

## SN54BCT241, SN74BCT241 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

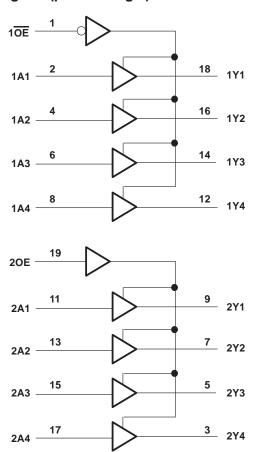
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### logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)



#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>		– 0.5 V to 7 V
Voltage range applied to any output in the		
Input clamp current, I <sub>IK</sub>		–30 mÅ
Current into any output in the low state: S	SN54BCT241	
	SN74BCT241	
Operating free-air temperature range: S	SN54BCT241	– 55°C to 125°C
\$	SN74BCT241	0°C to 70°C
Storage temperature range		– 65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



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#### recommended operating conditions

		SN54BCT241			SN74BCT241			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNII	
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V	
VIH	High-level input voltage	2		2			V		
VIL	Low-level input voltage	0.8				0.8	V		
lικ	Input clamp current	-18			-18	mA			
loh	High-level output current		-12			-15	mA		
lOL	Low-level output current	48				64	mA		
T <sub>A</sub>	Operating free-air temperature	-55 12 <b>5</b>		0		70	°C		

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN	SN54BCT241			SN74BCT241			
				MIN	TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT	
VIK		$V_{CC} = 4.5 \text{ V},$	I <sub>I</sub> = -18 mA			-1.2			-1.2	V	
			$I_{OH} = -3 \text{ mA}$	2.4	3.3		2.4	3.3			
Vон		V <sub>CC</sub> = 4.5 V	$I_{OH} = -12 \text{ mA}$	2	3.2					V	
			$I_{OH} = -15 \text{ mA}$				2	3.1			
V -		V 45 V	I <sub>OL</sub> = 48 mA		0.38	0.55				V	
VOL		V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 64 mA					0.42	0.55		
II		V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 7 V			0.1			0.1	mA	
ΊΗ		V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20			20	μΑ	
1	1OE or 2OE	V 55V	V 05V			-1			-1	A	
I L	Any A input	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.5 V			-1.6			-1.6	mA	
lozh		V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.7 V			50			50	μΑ	
lozL		$V_{CC} = 5.5 \text{ V},$	V <sub>O</sub> = 0.5 V			-50			-50	μΑ	
los‡		V <sub>CC</sub> = 5.5 V,	VO = 0	-100		-225	-100		-225	mA	
ІССН		V <sub>CC</sub> = 5.5 V,	Outputs open		23	43		23	43	mA	
ICCL		V <sub>CC</sub> = 5.5 V,	Outputs open		53	85		53	85	mA	
ICCZ		V <sub>CC</sub> = 5.5 V,	Outputs open		4	10		4	10	mA	
Ci		V <sub>CC</sub> = 5 V,	V <sub>I</sub> = 2.5 V or 0.5 V		6			6		pF	
Co		V <sub>CC</sub> = 5 V,	V <sub>O</sub> = 2.5 V or 0.5 V		11			11		pF	

<sup>†</sup> All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C. ‡ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

## SN54BCT241, SN74BCT241 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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#### switching characteristics (see Note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC}$ = 5 V, $C_L$ = 50 pF, R1 = 500 Ω, R2 = 500 Ω, $T_A$ = 25°C			$V_{CC}$ = 4.5 V to 5.5 V, $C_L$ = 50 pF, R1 = 500 Ω, R2 = 500 Ω, $T_A$ = MIN to MAX $^\dagger$				UNIT
			′BCT241			SN54B	CT241	SN74BCT241		
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	А	Y	0.5	2.5	4.5	0.5	5.2	0.5	4.9	ns
<sup>t</sup> PHL			'	1	3	5.4	1	6.3	1	5.9
<sup>t</sup> PZH	OE or OE	Y	1	5.7	7.8	1	9.1	1	8.7	ns
t <sub>PZL</sub>			1	5.2	8.6	1	10	1	9.4	115
<sup>t</sup> PHZ	OE or OE	Υ	1	5.8	6.8	1	8.4	1	8.1	ns
tPLZ		Į.	1	7	8.1	1	11	1	9.9	113

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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